

Advanced Power MOSFET

SFF9240

FEATURES

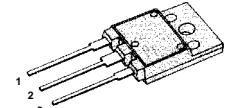
- Avalanche Rugged Technology
- Rugged Gate Oxide Technology
- Lower Input Capacitance
- Improved Gate Charge
- Extended Safe Operating Area
- Lower Leakage Current : 10 µA (Max.) @ $V_{DS} = -200V$
- Lower $R_{DS(ON)}$: 0.344 Ω (Typ.)

$BV_{DSS} = -200 V$

$R_{DS(on)} = 0.5 \Omega$

$I_D = -7.6 A$

TO-3PF



1.Gate 2. Drain 3. Source

Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage	-200	V
I_D	Continuous Drain Current ($T_C=25^\circ C$)	-7.6	A
	Continuous Drain Current ($T_C=100^\circ C$)	-5.3	
I_{DM}	Drain Current-Pulsed ①	30	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy ②	770	mJ
I_{AR}	Avalanche Current ①	-7.6	A
E_{AR}	Repetitive Avalanche Energy ①	6.0	mJ
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns
P_D	Total Power Dissipation ($T_C=25^\circ C$)	60	W
	Linear Derating Factor	0.48	$W/\text{ }^\circ C$
T_J, T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$
	Maximum Lead Temp. for Soldering Purposes, 1/8 " from case for 5-seconds	300	

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	2.08	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient	--	40	

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Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	-200	--	--	V	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=-250\mu\text{A}$
$\Delta \text{BV}/\Delta T_J$	Breakdown Voltage Temp. Coeff.	--	-0.16	--	V°C	$\text{I}_D=-250\mu\text{A}$ See Fig 7
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	-2.0	--	-4.0	V	$\text{V}_{\text{DS}}=-5\text{V}, \text{I}_D=-250\mu\text{A}$
I_{GSS}	Gate-Source Leakage , Forward	--	--	-100	nA	$\text{V}_{\text{GS}}=-30\text{V}$
	Gate-Source Leakage , Reverse	--	--	100		$\text{V}_{\text{GS}}=30\text{V}$
I_{DSS}	Drain-to-Source Leakage Current	--	--	-10	μA	$\text{V}_{\text{DS}}=-200\text{V}$
		--	--	-100		$\text{V}_{\text{DS}}=-160\text{V}, \text{T}_C=125^\circ\text{C}$
$\text{R}_{\text{DS(on)}}$	Static Drain-Source On-State Resistance	--	--	0.5	Ω	$\text{V}_{\text{GS}}=-10\text{V}, \text{I}_D=-3.8\text{A}$ ④
g_f	Forward Transconductance	--	5.3	--	S	$\text{V}_{\text{DS}}=-40\text{V}, \text{I}_D=-3.8\text{A}$ ④
C_{iss}	Input Capacitance	--	1220	1585	pF	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=-25\text{V}, f=1\text{MHz}$ See Fig 5
C_{oss}	Output Capacitance	--	207	310		
C_{rss}	Reverse Transfer Capacitance	--	81	120		
$t_{d(\text{on})}$	Turn-On Delay Time	--	16	40	ns	$\text{V}_{\text{DD}}=-100\text{V}, \text{I}_D=-11\text{A}, \text{R}_G=9.1\Omega$ See Fig 13 ④ ⑤
t_r	Rise Time	--	23	55		
$t_{d(\text{off})}$	Turn-Off Delay Time	--	54	115		
t_f	Fall Time	--	19	50		
Q_g	Total Gate Charge	--	46	59	nC	$\text{V}_{\text{DS}}=-160\text{V}, \text{V}_{\text{GS}}=-10\text{V}, \text{I}_D=-11\text{A}$
Q_{gs}	Gate-Source Charge	--	9.2	--		$\text{See Fig 6 \& Fig 12}$ ④ ⑤
Q_{gd}	Gate-Drain(" Miller") Charge	--	22.9	--		

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_S	Continuous Source Current	--	--	-7.6	A	Integral reverse pn-diode in the MOSFET
I_{SM}	Pulsed-Source Current ①	--	--	-30	A	
V_{SD}	Diode Forward Voltage ④	--	--	-5.0	V	$\text{T}_J=25^\circ\text{C}, \text{I}_S=-7.6\text{A}, \text{V}_{\text{GS}}=0\text{V}$
t_{rr}	Reverse Recovery Time	--	180	--	ns	$\text{T}_J=25^\circ\text{C}, \text{I}_F=-11\text{A}$
Q_{rr}	Reverse Recovery Charge	--	1.24	--	μC	$d\text{I}_F/dt=100\text{A}/\mu\text{s}$ ④

Notes :

- ① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- ② $L=20\text{mH}, \text{I}_{\text{AS}}=-7.6\text{A}, \text{V}_{\text{DD}}=-50\text{V}, \text{R}_G=27\Omega^*, \text{Starting } \text{T}_J=25^\circ\text{C}$
- ③ $\text{I}_{\text{SD}} < -11\text{A}, d\text{I}/dt < 450\text{A}/\mu\text{s}, \text{V}_{\text{DD}} < \text{BV}_{\text{DSS}}$, Starting $\text{T}_J=25^\circ\text{C}$
- ④ Pulse Test : Pulse Width = $250\mu\text{s}$, Duty Cycle $< 2\%$
- ⑤ Essentially Independent of Operating Temperature

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Fig 1. Output Characteristics

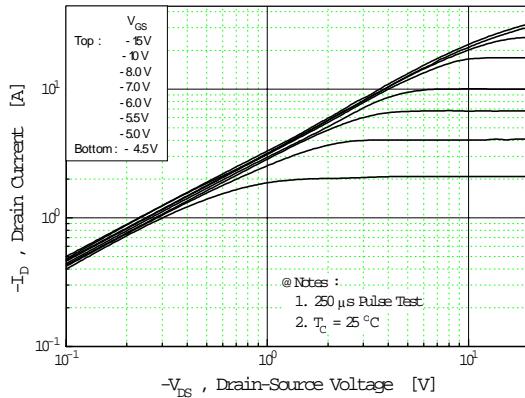


Fig 2. Transfer Characteristics

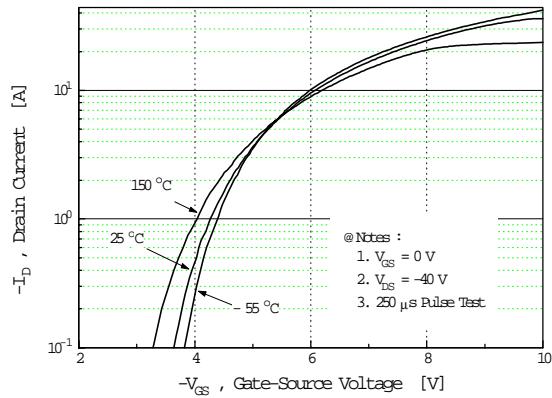


Fig 3. On-Resistance vs. Drain Current

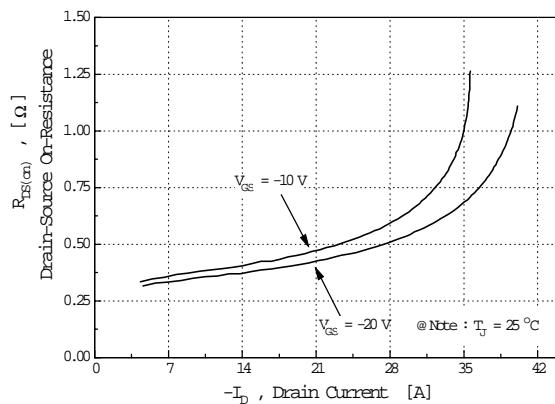


Fig 4. Source-Drain Diode Forward Voltage

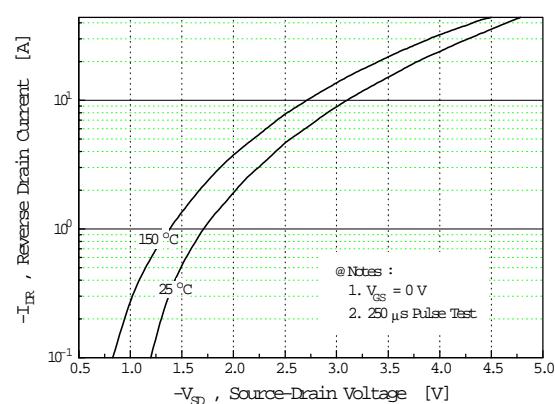


Fig 5. Capacitance vs. Drain-Source Voltage

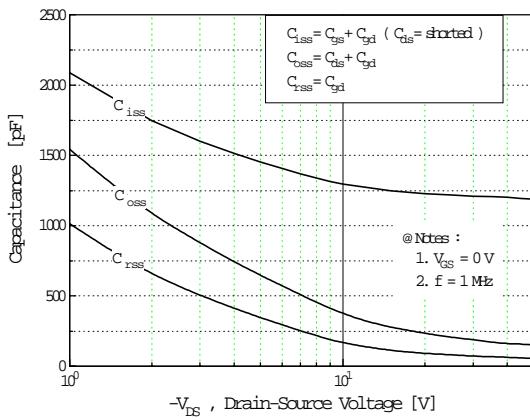
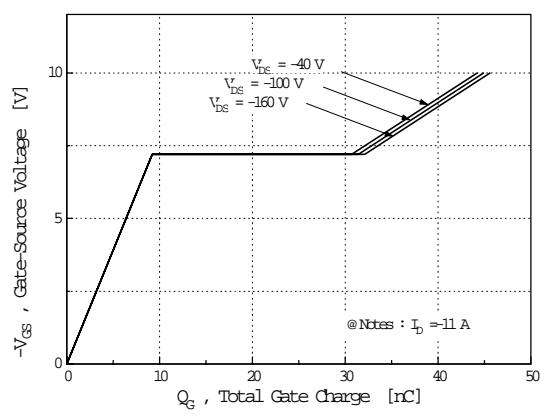
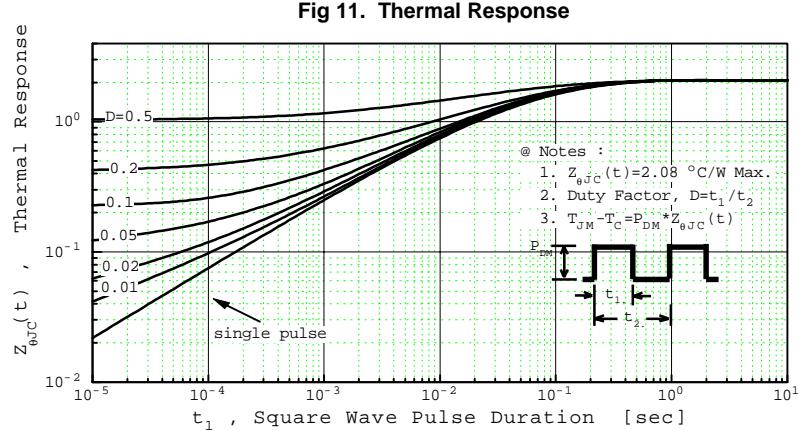
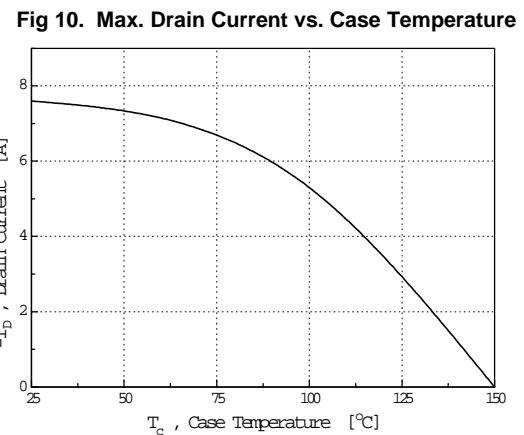
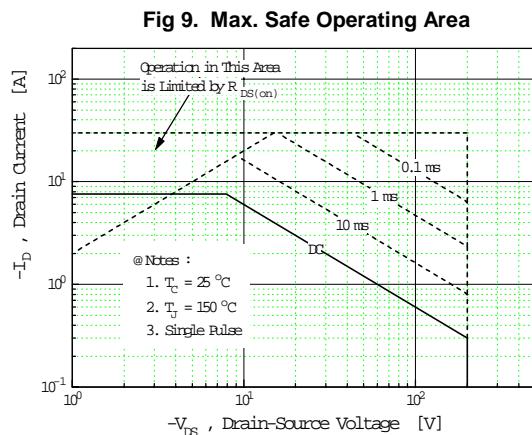
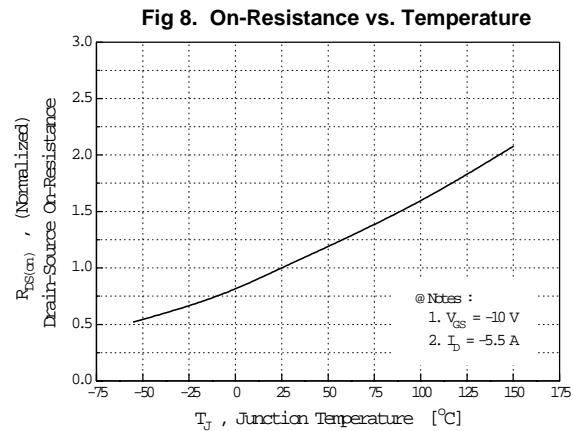
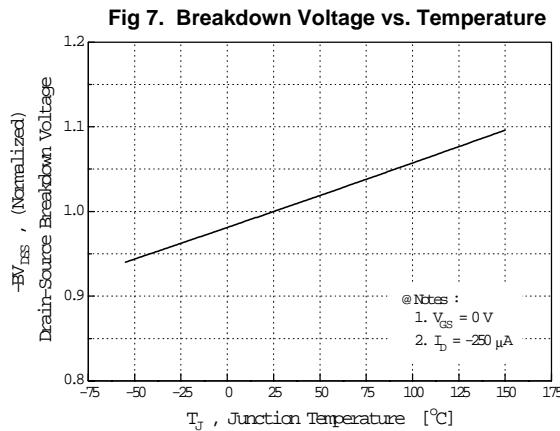


Fig 6. Gate Charge vs. Gate-Source Voltage



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Fig 12. Gate Charge Test Circuit & Waveform

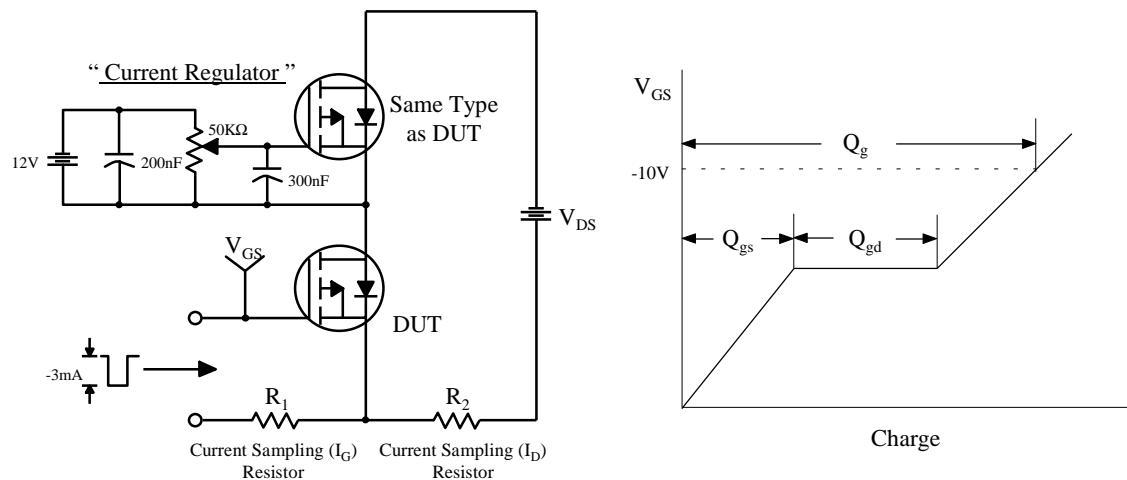


Fig 13. Resistive Switching Test Circuit & Waveforms

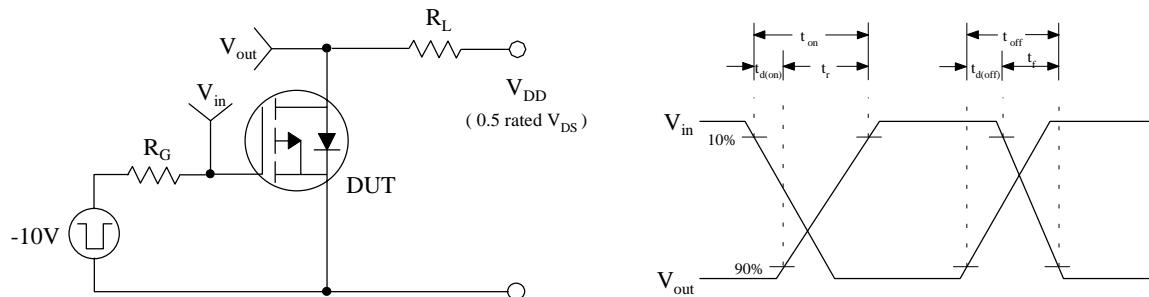
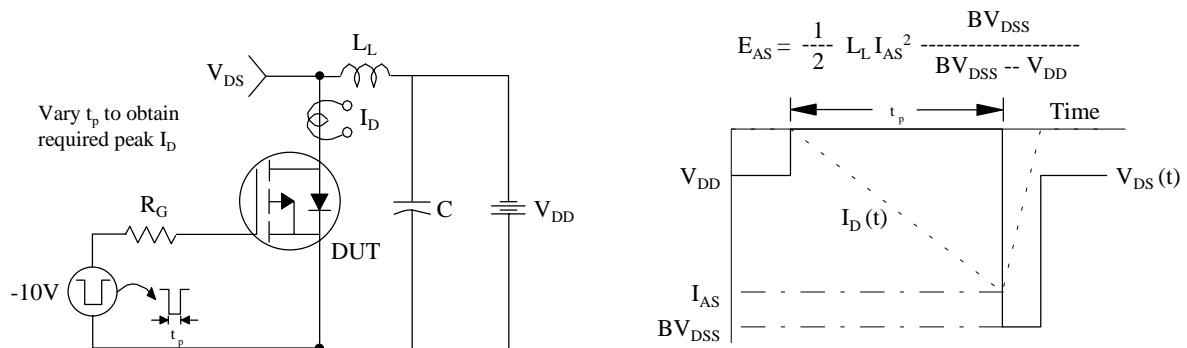


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

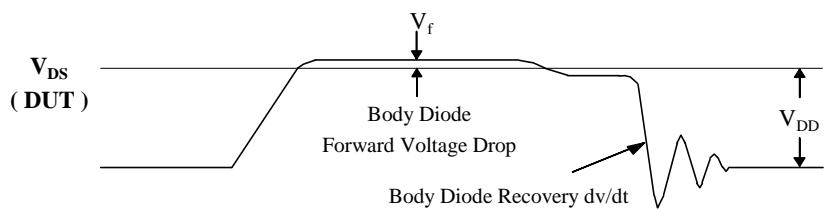
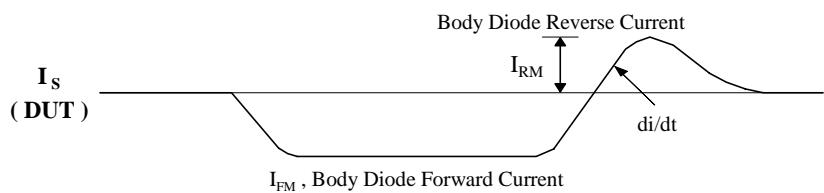
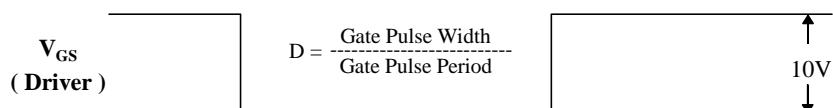
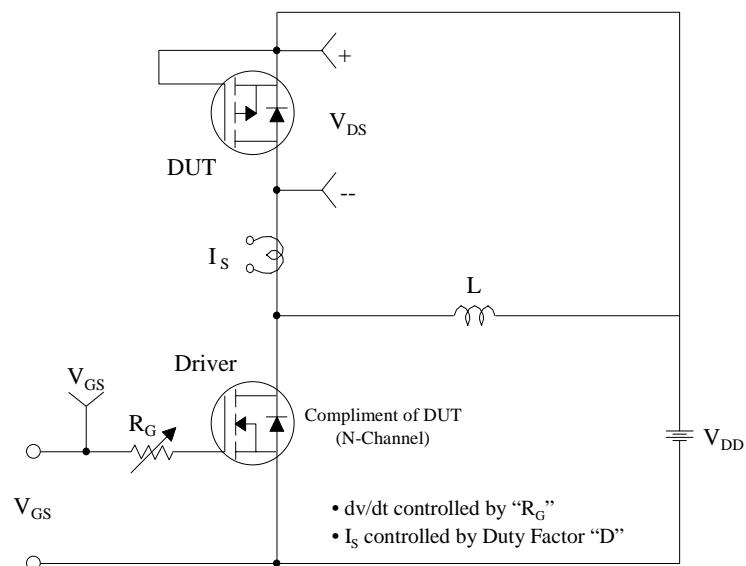


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Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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